

Accelerate Yield Investigations & Root Cause Analysis

The Challenge:

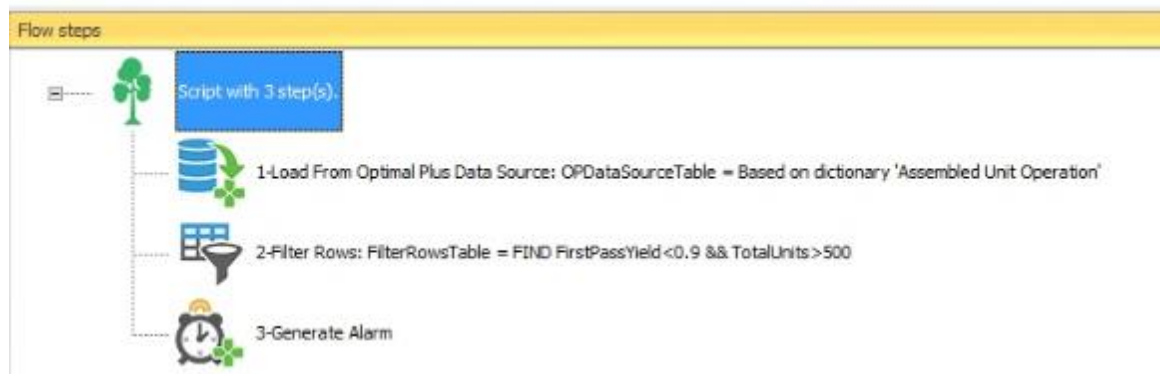
Delays in investigating yield-related problems and performing Root Cause Analysis (RCA) can lead to latent damage control. Statistics show that 20-25% of an engineer's time is spent on investigating and fixing issues, with a significant portion of this time devoted to collecting the data.

The Solution:

Global Ops for Electronics provides automated detection and assisted RCA capabilities for intermittent NTF, enabling electronics manufacturers to reduce the cost of non-conformance by 10-100X and reduce their warranty reserves (typically 1-2% of revenue).

Using Global Ops, as illustrated in the diagrams below, engineers can apply rules to automatically detect yield drops. Role-based dashboards assist in the analysis and aid in unveiling hidden trends. Findings can be easily shared with internal teams; timely feedback to critical component suppliers helps prevent "stock outs" that lead to line stoppage & revenue interruption.

1. Sequoia Rule – Low Yielding Products

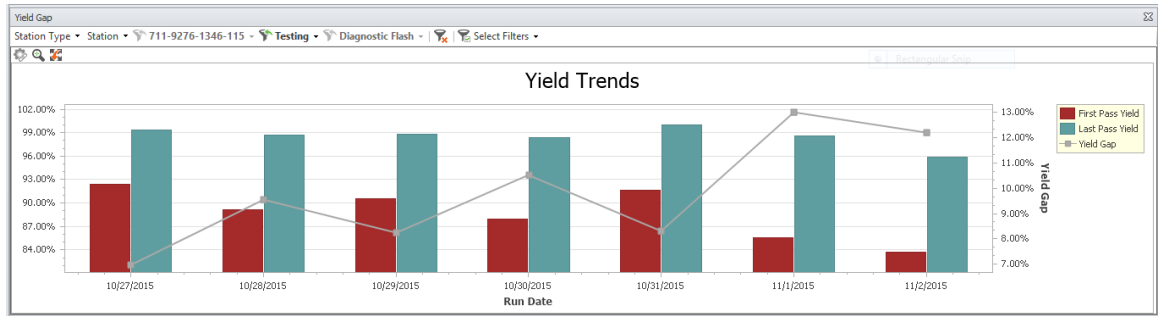


2. Management Dashboard – Yields
Login and view details

Critical Product Launch Dashboard

711-9276-1346-115 Visual Inspection F... Station Type Station Operation Type Select Filters

Operation	Total Units	Fail Units	First Pass Yield	Last Pass Yield
Diagnostic Flash	6,943	111	88.02 %	98.40 %
WiFi Test (cabled)	6,798	31	88.88 %	99.54 %
OS Flash Programming	6,833	62	89.24 %	99.09 %
Pattern Test	6,766	5	99.04 %	99.93 %
Optical Inspection Top	303	0	100.00 %	100.00 %
Solder Paste Inspection Topside	1,046	0	100.00 %	100.00 %
Solder Top	283	0	100.00 %	100.00 %
PC Board Test	1,048	0	100.00 %	100.00 %
Solder Bottom	684	0	100.00 %	100.00 %
Optical Inspection Bottom	665	0	100.00 %	100.00 %
Virtual Inspection	6,987	0	100.00 %	100.00 %
val-8642	641	0	100.00 %	100.00 %



3. Product Manager Dashboard

Review Error Trends



4. Process Engineer Dashboard
View Top Component Failures

Component Failures

711-9276-1346-115 | Diagnostic Flash |

Select Filters

	Failing Comp Location	Component Rework Count
▶	A-25	61
	A-14	6
	N/A	3
	A-01	2
	X-32	1
	X-15	1